Reliability Modelling of Phased Mission Multi-State Systems via a Scenario Inference Method

LI YINGYI

School of Reliability and System Engineering

Beihang University, Beijing, China

Outline

Background and Introduction



FST Models for Failure Mechanism Dependence



FST Models for Multi-state Systems



FST Models for Phased-mission Systems



Case Study and Conclusion





Data-based methods (Black box methods)



- How about it is very hard to get enough samples to be tested to get enough data about the product life?
- How about the product enjoys a pretty good quality which means you have to spend a quite long time (maybe the whole life) to get the data, even using the accelerating technology?
- How about the data is not reliable or not correct?

PoF methods (White box methods)

Generalized Damage Parameter, GDP



 $N = c(\Delta W_s)^{-\frac{1}{\alpha}} \left(\frac{v_t}{2}\right)^{1-k} \left(\frac{v_c}{v_t}\right)^n$

For a complicated system, a single model is too weak to describe the process of the system failure, for the failure not only has the relationship with one single mechanism or several independent mechanisms, also relies on the correlations among the failure mechanism, system structure and so on. For the multi-state systems and phased-mission systems, the situation even more complex.

O1 Background and Introduction

Generate a system model

Petri Net model just for a simple component



Generate a system model

We have a dream!

- Can we generate a model automatically?
- Can we get the failure path of the system automatically?

The first step:

We need to draw a map!

BDD model just for a simple system with six components





FST Models for Failure Mechanism Dependence

O2 FST Models for Failure Mechanism Dependence

2.2 2.3 2.4 Competition 2.1 M₁ min MACO M_i M. M_n . . . M_n

Failure Mechanism Tree

Failure Scenario Tree

o F

o F

o F

Every possibility of the failure is shown in a failure scenario tree, which means the FST can draw all possible path from very beginning to the very end (failure or some certain event). Such characteristic is the reason that the FST can be the base of automatic modelling.

Failure probability of the system

$$F(t) = 1 - \prod_{i=1}^{n} \left[1 - \int_{0}^{t} \underbrace{f_{i}(\sigma)}_{\sigma} d\sigma \right]$$
 failure distribution function of M_i







$$F(t) = P\left(\frac{1}{\sum_{i=1}^{n} \frac{\lambda_i}{t_i}} \le t\right)$$





FST Models for Multi-state Systems

O3 FST Models for Multi-state Systems





- The Time Order FST is used to generate model for multi-state components.
- A switch between two states refers to a stage.
 (3 states 2 stages)
- The terminal event represent multiple states, rather than just one result (like 'failure' in the binary system)

3.1 3.2 Fault Order FST

Fault order FST is used on the level of component and subsystem, which means the event in the FST is the state of the component, rather than the failure mechanism dependence.





- Only the change of the state will be shown in the FST, in order to condense the size of the FST.
- Fault (or state-change) order of the components needs to be determined before drawing the Fault Order FST.

A-1 \cap B-2, A-1 \cap B-3, impossible

• The relationship between the state of the system and its components needs to be determined.

S-1: A-1 ∩ B-1

- **S-2:** A-2 ∩ B-1 or A-2 ∩ B-2
- S-3: A-2 ∩ B-3 or A-3





FST Models for Phased-mission Systems



- 4.1 4.2 Multi-state EOST
 - In terms to a phased-mission multi-state system, it could be under different states in the same phase or mission.
 - The EOST, which shows the binary state, is upgraded into MS-EOST to draw the multiple state.



Ph*i-j* or MS-*j* means the system in phase *i* or the current mission is at state *j*

MS-1: Ph1-1 ∩ Ph2-1

MS-2: Ph1-1 ∩ Ph2-2, Ph1-2 ∩ Ph2-1 Ph1-2 ∩ Ph2-2

MS-3: Ph1-1 ∩ Ph2-3, Ph1-2 ∩ Ph2-3 Ph1-3





An electrical system, which is regarded as a PM-MSS, is required to perform a mission with four phases. The performing order and the duration of each phase are shown as:



Phase 1, 2, 4





D5 Case Study and Conclusion 1 Description 5.2 5.3					
	system State	e Definition			
	Phase 1, 2, 4	Phase 3	Mission		
State 1	V is in state 1 and at least two of three ICs are in state 1.	All components are in state 1.	All phases are in state 1.		
State 2	V is in state 2 and no more than one IC is in state 3. Or V is in state 1 and at least one of the two best functioning ICs among three ICs is in state 2.	At least one of the components is in state 2 and none is in state 3.	At least one of the phases is in state 2 and none is in state 3.		
State 3	V is in state 3 or at least two of three ICs are in state 3.	At least one of the components is in state 3.	At least one of the phases is in state 3.		



5.1 Description 5.2 5.3

Failure Mechanism and Correlation

Component	Mechanism	Correlation		
X 7	Crack	Trigger by shock	Competition	
V	VF	/		
	TDDB	Accumulation		
IC ₁	NTBI		Competition	
	EM	/		
IC	Creep	Acceleration		
IC_2	EM	Acceleration		
	VF	Accumulation	Competition	
IC ₃	TF	Accumulation		
	EM	/		

- VF vibration fatigue
- **TF** thermal fatigue
- TDDB time-dependent dielectric

breakdown

- **NBTI** negative bias temperature instability
- EM electrical migration



Time Order FST for every component

Component Mechanism		Correlation			
X 7	Crack	Trigger by shock			
V	VF	/	Competition		

5.3

Level



Failure Mechanism

V-1 The state of V has never changed, so neither Crack nor VF has effect on V.

V-2 Due to the continuing influence of VF, it is possible that V change its state from V-1 to V-2.

V-3 (1) no Crack
Based on the state V-2, the continuing influence of VF can change the state into V-3.
(2) Crack occurs.
No matter when the Crack starts, V will change its state

into V-3.





State 1	All components are in state 1.
State 2	At least one of the components is in state 2 and none is in state 3.
State 3	At least one of the components is in state 3.

0	5 Case Stu	idy and Conclusion						<u>PSAM</u> 14
5.	1 5.2 M	lodelling Generation 5.3	Level	Failure	Mechanisn	Com	oonent	Phase
Mu	Iti-state E	vent Order FST for miss	o— ion	Ph1-1	Ph2-1	Ph3-1	Ph4-1	MS-1 MS-2
		Mission			_	Ph3-2	Ph4-3 Ph4-1/2	MS-3 MS-2
	State 1	All phases are in state 1.				Ph3-3	— Ph4-3 — C	MS-3 MS-3
	State 2	At least one of the phases is in state 2 and none is in state 3.		- Ph1-2	Ph2-2 Ph2-3 Ph2-3 Ph2-1/2	Ph3-1/2 Ph3-3 Ph3-1/2	Ph4-1/2	 MS-2 MS-3 MS-3 MS-3 MS-3 MS-2
	State 3	At least one of the phases is in state 3.						MS-3 MS-3
				Ph1-3 -				MS-3 MS-3

05 Case Study and Conclusion

5.1 5.2 5.3 Calculating Results



- The value of reliability of the binary-state condition is larger than that of the multi-state condition.
- The probability of state 2 is generally increased first and then decreased. <not monotone>
- The sum of all state probabilities at the same time is always equal to 1.

- The state probability curve of a multi-phase system is not as smooth as that under single-phase condition, and an inflection point often occurs when phase changed.
- The evaluation of system reliability and state probability considering multi-state and multi-phase becomes closer to the engineering practice.



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